Press Release

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New AVT-2000 for Early Defect Detection in HDD Substrate Processing

'Game changing' technology to detect defects at the Substrate Grind, Nickel Plate and First Polish process steps for improved hard disk drive reliablity.

SAN JOSE, CA, February 16th, 2015 – Polytec, a California company, announced its new AVT-2000, which is designed to give hard disk drive (HDD) substrate makers a 'game changing' technology to detect defects at the Substrate Grind, Nickel Plate and First Polish process steps. Before the AVT-2000 this was not possible. Defects could only be detected at the final substrate test, making it difficult to find the cause of the defect. In this competitive environment, HDD manufacturers have expressed the critical nature of finding defects earlier in their multi-step process. Polytec has responded to this requirement with an exciting new product.

Expedited recipe development is enabled by Polytec's proprietary Defect Classification Assistant (DCA), which allows the user to build detection algorithms with statistically based methodology. This groundbreaking technique takes defect detection and classification to a new level. Empirical methods are used in the DCA instead of the legacy 'trial and error' attempts.

HGST, a Western Digital Company, is the first adopter of this enabling technology, which will change the way failure analysis has been done for over 30 years. Root cause analysis will now be utilized to improve processes, reduce scrap/rework, capture excursions, and drive cost out of high volume manufacturing.

Polytec proudly releases the new AVT-2000 on the market. For any inquiries regarding the new testing solution please contact the Polytec Team at 949-943-3033.